

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/695,561	<b>Applicant(s)/Patent under Reexamination</b> PICCIALLO, MICHAEL J.
<b>Examiner</b> Amee A. Shah	<b>Art Unit</b> 3625	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner